

BIT AND BYTE TESTING PROCEDURES AS51



BIT AND BYTE TESTING PROCEDURES



2650 MICROPROCESSOR APPLICATIONS MEMO

SUMMARY

This applications memo describes several methods of testing the contents of the internal registers in the Signetics 2650 Microprocessor.

The following test examples are given:

- Specific bit(s) in a register.
- Positive, negative, or zero-contents of a register.
- Contents of a register compared with a value (equals, greater than, or less than).
- Interdigit-carry (IDC), overflow (OVF), and carry (C) flags in the program status word.

INTRODUCTION

As a result of an operation on register(s) of the 2650 register bank, five bits (bits 7, 6, 5, 2, and 0) in the Program Status Lower (PSL) portion of the Program Status Word (PSW) register can be affected.

7	6	5	4	3	2	1	0
CC1	CC0	IDC	RS	WC	OVF	COM	C.

PROGRAM STATUS LOWER (PSL)

These bits are affected as follows:

CC1, CC0: Condition Code Bits

			RESULT OF		
CONDITION		LOAD/STORE, ARITHMETIC,	COMPARE	SELECTIVE TESTS ON	
CC1	CC0	LOGICAL INSTRUCTIONS	INSTRUCTION	BITS (TMI, TPSU, & TPSL)	
0	0	Zero	Equal	All bits 1	
0	1	Positive	Greater Than		
1	0	Negative	Less Than	Not all bits 1	

IDC: Interdigit Carry/Borrow Bit

The IDC bit is affected by arithmetic operations as well as rotation.

0 = Interdigit borrow/no interdigit carry

1 = Interdigit carry/no interdigit borrow

OVF: Overflow Bit. Arithmetic Operation

The overflow bit in arithmetic operations is set as follows:

Operand 1 ± Operand 2→ Result

	ADD	SUB		
OPERAND 1	OPERAND 2	RESULT	OVF	OVF
+	+	+	0	0
+	+	_	1	0
+	_	+	0	0
+	_	_	0	1
_	+	+	0	1
-	+	_	0	0
_	_	+	1	0
-	-	-	0	0

OVF: Overflow Bit. Rotate Operation

Condition: WC = 1; if WC = 0, the OVF bit is not affected.

The overflow bit is set as follows:

OPERA		
BEFORE ROTATE	AFTER ROTATE	OVF
+	+	0
+	_	1
-	+	0
_	_	0

C: Carry/Borrow Bit

The Carry bit is affected by arithmetic operations as well as rotation.

0 = borrow/no carry

1 = carry/no borrow

BIT TESTING PROCEDURES

The bits of a register Rx (register zero Ro or any register R1, R2 or R3 in the selected register bank) can be tested as follows:

				B T E S	CYCLES
TEST FOR	'0' IN B	IT 3 OF Rx			
TMI, Rx	H'08'		1)	2	3
BCTR, 2	LBL	*Branch if bit 3 is zero.		2	3
				4	6
or:					
ANDI, Rx	H'08'		2)	2	2
BCTR, 0	ĿBL	*Branch if bit 3 is zero.		2	2 3
				4	5

While the second test is faster, it affects the contents of Rx.

BIT TESTING PROCEDURES (Continued)

TEST FOR '1' IN BIT 3 OF RX

TMI, Rx	H'08'		1)	2	3
BCTR, 0	LBL	*Branch if bit 3 is one.		2	3
				4	6

or:

ANDI, Rx	H'08'		2)	2	2
BCFR, 0	LBL	*Branch if bit 3 is one.		2	3
				4	5

While the second test is faster, it affects the contents of Rx.

TEST FOR '0' IN BIT 1 OR BIT 3 OR BIT 6 OF RX

TMI, R×	H'4A'		1)	2	3
BCTR, 2	LBL	*Branch if one of the		2	3
		tested bits is zero.		4	6

TEST FOR '1' IN BIT 1 OR BIT 3 OR BIT 6 OF Rx

ANDI, Rx	H'4A'		2)	2	2
BCFR, 0	LBL	*Branch if one of the		2	3
		tested bits is one.		4	5

TEST FOR '0' IN BIT 1 AND BIT 3 AND BIT 6 OF RX

ANDI, Rx	H'4A'		2)	2	2
BCTR, 0	LBL	*Branch if all tested		2	3
		bits are zero.		4	5

TEST FOR '1' IN BIT 1 AND BIT 3 AND BIT 6 OF RX

TMI, R×	H'4A'		1)	2	3
BCTR, 0	LBL	*Branch if all tested		2	3
		bits are one.		4	6

TEST FOR PATTERN IN Rx; e.g., x10xx01x

x = don't care

10RI, Rx	H'99'		2)	2	2
COMI, Rx	H'DB'			2	2
BCTR, 0	LBL	*Branch if pattern		2	3
		is true.		6	7

1) Contents of register Rx kept

BYTE TESTING PROCEDURES

TEST FOR POSITIVE, NEGATIVE AND ZERO

All of the tests described below must be preceded by an operation on Rx which updates the contents of the condition register, e.g., by instructions such as LOAD, ADD, AND, COMPARE, ROTATE, I/O, etc.

	CC	OPERATION
Test for $(Rx) \ge 0$	00 or 01	BCFR, 2
Test for $(Rx) > 0$	01	BCTR, 1
Test for $(Rx) = 0$	00	BCTR, 0
Test for $(Rx) \le 0$	10	BCTR, 2
Test for $(Rx) \leq 0$	00 or 10	BCFR, 1

TESTS ON THE CONTENTS OF A REGISTER BY USING COMPARE INSTRUCTIONS

Logical compare: (COM = 1 in PSL)

Comparison is made between two 8-bit unsigned binary numbers.

Arithmetic compare: (COM = 0 in PSL)

Comparison is made between two 8-bit signed numbers.

After execution of the logic or arithmetic compare instruction, the condition register (CC) is set to a specific value and tested as follows:

REGISTER-	REGISTER-TO-REGISTER COMPARE			
Instruction used: COMZ Rx	:	-		
RESULT	CC	TEST		
(Ro) ≥ (Rx)	00 or 01	BCFR, 2		
(Ro) > (Rx)	01	BCTR, 1		
(Ro) = (Rx)	00	BCTR, 0		
(Ro) < (Rx)	10	BCTR, 2		
(Ro) ≤(Rx)	00 or 10	BCFR, 1		

REGISTER TO CONSTANT OR MEMORY LOCATION				
Instructions used:				
COMI, RX	DATA			
COMR, RX	RELATIVE LOCATION OF DATA			
COMA, Rx I	LOCATION OF DATA			
RESULT	00	TEST		
V=VALUE	cc	IESI		
(Rx) ≥ V	00 or 01	BCFR, 2		
(Rx) > V	01	BCTR, 1		
(Rx) = V	00	BCTR, 0		
(Rx) < V	10	BCTR, 2		
(Rx) ≤ V	0 0 or 10	BCFR, 1		

Whenever a compare instruction is used, the IDC, OVF, or C bits in the PSL are *not* affected.

²⁾ Contents of register Rx lost

TEST ON OVERFLOW (OVF in PSL)

The overflow bit is affected whenever arithmetic or rotate instructions are executed.

The OVF bit is set during an addition whenever the two operands have the same sign and the result has a different sign. During a subtraction, the OVF bit is set when the operands differ in sign and the result has a different sign than the first operand.

Examples:

$$(+A) + (+B) = (-C)$$
 OVF

$$(-A) + (-B) = (+C)$$
 OVF
 $(+A) - (-B) = (-C)$ OVF

$$(-A) - (+B) = (+C)$$

H'04' Test: **TPSL** *OVF test

The OVF bit is set during rotate instructions with WC = 1 whenever the sign changes from positive to negative. If WC = 0, then rotate instructions do not affect the OVF bit.

Example:

RRR, Rx		*Rotate right
TPSL	H'04'	*Test OVF bit
BCTR.0	LBL	*Branch if OVF = se

TEST ON CARRY (C in PSL)

The carry bit is set to 1 by an add instruction that generates a carry and a sub-instruction that does not generate a borrow.

Example:

ADDITION

LODI, Rx H'88' ADDI, Rx H'99'

TPSL H'01'

*Test carry BCTR, 0 LBL *Branch if carry

SUBTRACTION

LODI, Rx H'40' SUBI, Rx H'30'

H'01' TPSL

BCTR, 0 LBL *Test borrow

*Branch if no borrow

When a rotate instruction is executed with WC = 1, the carry bit is also affected. Refer to the Signetics 2650 Microprocessor manual for a description of this operation.